Dr-Ragini Raj Srigh

[3]

## JAYPEE UNIVERSITY OF INFORMATION TECHNOLOGY, WAKNAGHAT TEST-1 EXAMINATION- SEPTEMBER -2018

## Ph.D. I Semester

COURSE CODE: 13P1WPH112 MAX. MARKS: 15 COURSE NAME: Materials Characterization **COURSE CREDITS: 3** MAX. TIME: 1 HRS Note: All questions are compulsory. Carrying of mobile phone during examinations will be treated as case of unfair means.  $[1 \times 3]$ Q.1. Write short notes on: a. Atomic scattering factor b. Particle size and crystallite size c. What contributes FWHM of XRD peak profile? Q.2. What are the characteristic and Bremsstrahlung radiations in X-ray generation process. Comment on K-alpha and K-beta radiations. [3] Q.3. What is the anatomy of the X-ray diffraction pattern? What can be determined from X-ray [3] data? Q.4. How to separate crystallite size broadening and strain broadening, present analytical method to do the same. [3]

O.5. How many types of signals are there in SEM? Which signals contributes most in SEM

image formation. Also discuss electron beam sample interaction in SEM.